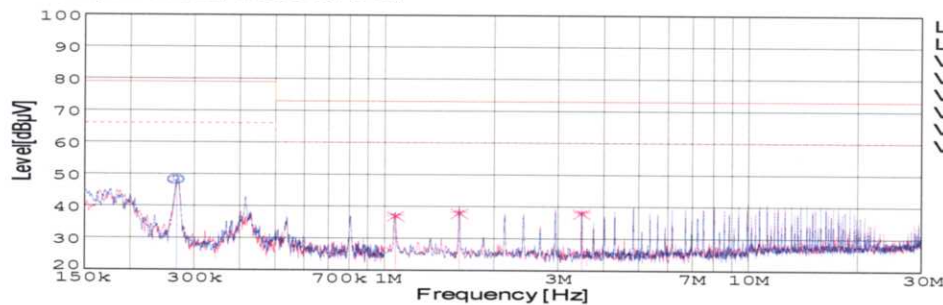


## DATA SHEET

Date		12-Mar-05	
Model	SUS102412	Temp.	25degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	C.Makino

### LINE CONDUCTION

Model Name : SUS102412  
 Model No. :  
 Serial No. :  
 Points : 4  
 Detector : PEAK/QP/Ave.  
 Line Mode : VA/VB  
 Power Supply : DC 24V  
 Limit1: [EN 55022] Class A(QP)  
 Limit2: [EN 55022] Class A(Ave.)  
 Temp. : 25degreeC  
 Humi. : 45%  
 Date : 2005/3/12 15:34  
 Test Equip. : R3132,ESPC  
 Load Line : 50mm  
 Comment : C.Makino



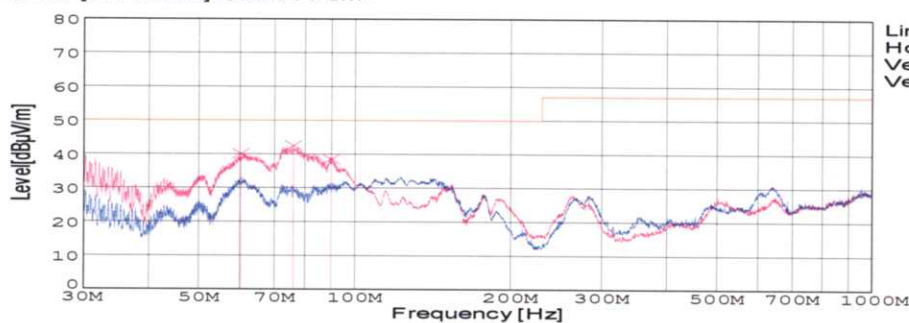
Limit1(QP) :  
 Limit2(Ave.) :  
 VA(PEAK) :  
 VB(PEAK) :  
 VA(QP) :  
 VA(Ave.) :  
 VB(QP) :  
 VB(Ave.) :

Vin: DC24V  
 Iout: 1A

Frequency [MHz]	Meter Reading (Ave.) [dBuV]	Meter Reading (QP) [dBuV]	Factor [dB]	Level(Ave.) [dBuV]	Level(QP) [dBuV]	Line	Limit(Ave.) [dBuV]	Limit(QP) [dBuV]	Margin(Ave.) [dB]	Margin(QP) [dB]
0.2681	38.7	38.2	9.8	48.5	48	VA	66	79	17.5	31
1.0713	27.3	27	9.9	37.2	36.9	VB	60	73	22.8	36.1
1.6065	28.4	27.9	9.9	38.3	37.8	VB	60	73	21.7	35.2
3.482	28.3	27.8	10	38.3	37.8	VB	60	73	21.7	35.2

### RADIATED EMISSION

Model Name : SUS102412  
 Model No. :  
 Serial No. :  
 Points : 3  
 Detector : PEAK/QP  
 Polarization : Vertical  
 Power Supply : DC 24V  
 Limit: [EN 55022] Class A<3m>  
 Temp. : 25degreeC  
 Humi. : 45%  
 Date : 2005/3/9 15:32  
 Test Equip. : R3132,ESPC  
 Load Line : 50mm  
 Comment : C.Makino



Limit(QP) :  
 Horizontal(PEAK) :  
 Vertical(PEAK) :  
 Vertical(QP) :

Vin: DC24V  
 Iout: 1A

Frequency [MHz]	Meter Reading (QP) [dBuV]	Ant. Type	Antenna Factor [dB/m]	Cable & Preamp [dB]	Level(QP) [dBuV/m]	Angle [°]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]
60.315	67.5	BL	4.7	-32	40.2	194	109	Vert.	50	9.8
76.116	68	BL	6.5	-31.9	42.6	225	106	Vert.	50	7.4
90.053	62	BL	8.5	-31.8	38.7	203	113	Vert.	50	11.3

# COSEL

## Conditions

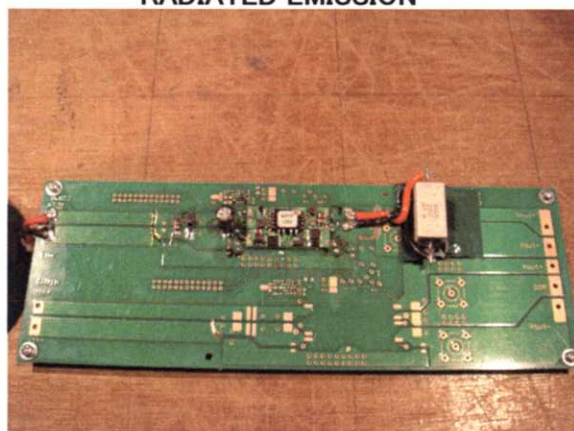
Test : EMI  
Model Name : SUS/SUW1024

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

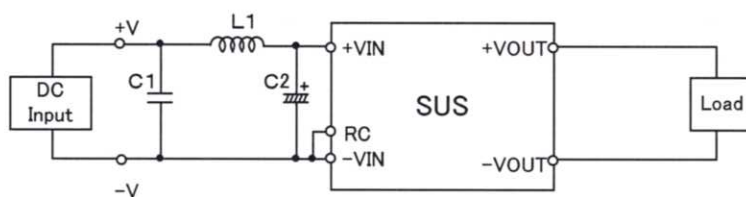


Fig.1 Testing circuitry 1

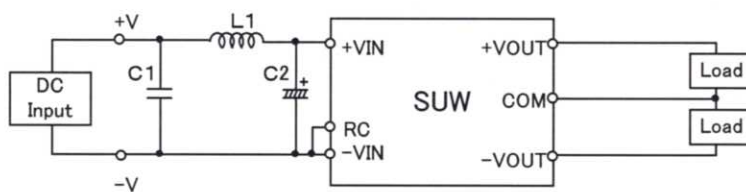


Fig.2 Testing circuitry 2

L1 : 2.2 $\mu$ H	CY3H-2R2	(KORIN ELECTRONICS)
C1 : 50V 3.3 $\mu$ F	C3225JB1H335M	(TDK)
C2 : 50V 100 $\mu$ F	UPM1H101M	(NICHICON)